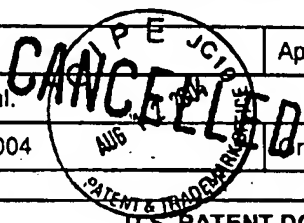




INFORMATION DISCLOSURE CITATION

OMB No. 0651-0011

Atty. Docket No.	3180.0350	Appln. No.	10/760,522
Applicant	Nakamura et al.		
Filing Date	January 21, 2004	Group:	<del>Unknown</del> 21 23



U.S. PATENT DOCUMENTS						
Examiner Initial*	Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate
/DC/	5,889,686	3/30/99	Mimotoji et al.			

FOREIGN PATENT DOCUMENTS						
	Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No
/DC/	2000-29217	1/28/00	Japan			Abstract
/DC/	4-44312	2/14/92	Japan			Abstract
/DC/	1-188859	7/28/89	Japan			Abstract

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
/DC/	Nakamura et al., "Influence of Alkaline Concentration Variation on CD in KrF Resist Development," Journal of Photopolymer Science and Technology (4/20/01), pp. 435-438
/DC/	Nakamura et al., "Impact of Development Reaction Products on CD in View of Developer Alkaline Concentration Deviation," SPIE (2001), p. 729

Examiner /Dwin Craig/ (08/07/2007)	Date Considered
*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	
Form PTO 1449	Patent and Trademark Office - U.S. Department of Commerce

IDS Form PTO/SB/08: Substitute for form 1449A/PTO			<b>Complete if Known</b>		
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  <i>(Use as many sheets as necessary)</i>			Application Number	10/760,522	
			Filing Date	January 21, 2004	
			First Named Inventor	Hiroko Nakamura	
			Art Unit	2123	
			Examiner Name	D. Craig	
Sheet	1	of	1	Attorney Docket Number	3180.0350



U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS					
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Document Number	Issue or Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			

**Note:** Copies of the U.S. Patent Documents are not Required in IDS filed after October 21, 2004

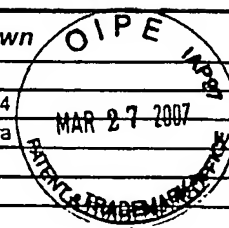
FOREIGN PATENT DOCUMENTS						
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation <sup>6</sup>
		Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)				
/DC/		JP 3-165510	07-17-1991	Toshiba Corp.		Abstract

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation <sup>6</sup>
/DC/		Notice of Grounds for Rejection issued by the Japanese Patent Office on May 22, 2007, for Japanese Patent Application No. 2003-012526, and English-language translation thereof	

Examiner Signature	/Dwin Craig/ (08/07/2007)	Date Considered	
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IDS Form PTO/SB/08: Substitute for form 1449A/PTO		<b>Complete if Known</b>	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)		Application Number	10/760,522
		Filing Date	January 21, 2004
		First Named Inventor	Hiroko Nakamura
		Art Unit	2123
		Examiner Name	Dwin M. Craig
Sheet	1	of	1
		Attorney Docket Number	3180.0350



U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS					
Examiner Initials	Cite No. <sup>1</sup>	Document Number	Issue or Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
		US-			
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		US-			

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FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation <sup>6</sup>
		Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)				
/DC/		JP 11-214373	08/06/1999	Chiharu et al.		Abstract

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation <sup>6</sup>
/DC/		Copy of Official Action Letter issued on February 20, 2007, in the counterpart Japanese Application 2003-012526 and an English abstract thereof.	Yes

Examiner Signature	/Dwin Craig/ (08/07/2007)	Date Considered	
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